

Monday 12 May

15:10

Updates on Simulations Session 15:10-15:25 CMOS simulation and connection between device-level and electronics simulations 15:25-15:40 Other detectors/technologies/activities Speaker Evridki Chatzianagnostou 15:40-15:55 Newly measured semiconductor properties 15:55-16:10 Radiation damage: validation with measurements and development of highfluence models 16:10-16:25 Time dependent electric/weighting field 16:25-16:40 Simulation tools development 16:40